MODIFIED PTO/SB/08 (08-00)

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Substitute for form 1449B/PTO	Complete if Known				
INFORMATION DISCLOSURE	Application Number	Unassigned 11151724			
STATEMENT BY APPLICANT	Filing Date	October 18, 2004			
Date Submitted: October 18, 2004	First Named Inventor	Davor PROTIC			
Date Submitted. October 16, 2004	Group Art Unit	Unassigned			
(use as many sheets as necessary)	Examiner Name	Unassigned			

**Attorney Docket Number** 

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				U.S. PATENT DOCUMENTS	3	
Examiner Cite No.1		U.S. Patent	Document	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
SL	A1	6,175,120	B1	McGREGOR et al.	01-16-2001	
SL	A2	5,164,809		STREET et al.	11-17-1992	

	FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No. <sup>1</sup>	For Office <sup>3</sup>	eign Patent D	Ocument Kind Co (if know	ode <sup>5</sup>	Name of Patentee or Applicant of Cited Documents	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>6</sup>
SL	A3	H. BECKER et al., "New Developments in Double Sided Silicon Strip Detectors", IEEE Transactions on Nuclear Science, April 1990, pages. 101-106, vol. 37, no. 2	
SL	A4	P. HOLL, et al., "A Double-Sided Silicon Strip Detector with Capacitive Readout and a New Method of Integrated Bias Coupling", IEEE Transactions on Nuclear Science, February 1989, pages 251-255, vole. 36, no. 1	
SL	A5	H. BECKER et al., "Readout of Doublesided Silicon Strip Detectors With High Density Integrated Electronics", IEEE Transactions on Nuclear Science, February 1989, vol. 36, no. 1 pg. 246-250	

Examiner Signature	/Shun Lee/	Date Considered	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached.

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Complete if Known 10/511,734 **Application Number** 10/18/2004 Filing Date First Named Inventor Davor PROTIC **Group Art Unit** Unassigned

Unassigned

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**Date Submitted:** JAN 0 4 2005 (use as many sheets as necessary)

Substitute for form 1449B/PTO

INFORMATION DISCLOSURE

STATEMENT BY APPLICANT

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			U.S. PATENT DOCUMENTS	•	
	U.S. Patent Document			Date of Publication of	Pages, Columns, Lines, Where Relevant
No.1	Number	Kind Code <sup>2</sup> (# known)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear
	Cite No.1	Cite	Cite No.1 Number Code <sup>2</sup> (#	Cite No. Number  U.S. Patent Document Kind Code <sup>2</sup> (#  Name of Patentee or Applicant of Cited Document	Cite No. Number Code <sup>2</sup> (# Name of Patentee or Applicant of Cited Document MM-DD-YYYY

**Examiner Name** 

**Attorney Docket Number** 

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Examiner Initials*	Cite No.1	For Office <sup>3</sup>	eign Patent (	ocument Kind Code <sup>5</sup>	Name of Patentee or Applicant of Cited Documents	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant	
		Onice	Number	(if known)			Figures Appear_	T°

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Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	۳
SL	B1	G. RIEPE et al., "A High Purity Germanium Position-Sensitive Detector for Positron Annihilation Experiments", Proc. 5 <sup>th</sup> Int. Conf. Positron Annihilation, 1979, pages 371-373.	
SL	B2	M. BETIGERI et al., "The germanium wall of the GEM detector system", Nuclear Instruments & Methods in Physics Research – Section A 421, 1999, pages 447-457.	
SL	В3	P.N. LUKE et al., "A 140-element Ge Detector Fabricated with Amorphous Ge Blocking Contacts", IEEE Transactions on Nuclear Science, August 1994, pages 976-978, Vol. 41, No. 4.	
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